



10/8/10

**RELIABILITY MONITOR REPORT
FOR**

MFN 3 μ m Silicon Gate CMOS (S3)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX197BCWI+	MAX3209EEUU	MAX3241EEUI+	MAX705ESA+	MAX706ESA+
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 99991 QUANTITY: 602 FAILS: 0 FITS: 1.1

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2009 and 9/30/2010 .

Process Information:

Process Description: MFN 3µm Silicon Gate CMOS (S3)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0935	MAX197BCWI+	135C	1000 HRS	46	0	NGPBD3586Q1
HIGH TEMP OP LIFE	0935	MAX197BCWI+	135C	1000 HRS	46	0	NGPBD3586Q2
HIGH TEMP OP LIFE	0935	MAX197BCWI+	135C	1000 HRS	46	0	NGPBD3586Q3
HIGH TEMP OP LIFE	0943	MAX706ESA+	135C	1000 HRS	80	0	NTOBI2079BB
HIGH TEMP OP LIFE	1010	MAX3241EEUI+	135C	1000 HRS	45	0	N4Q0CA026Q1
HIGH TEMP OP LIFE	1010	MAX3241EEUI+	135C	1000 HRS	45	0	N4Q0CA026Q2
HIGH TEMP OP LIFE	1010	MAX3241EEUI+	135C	1000 HRS	45	0	N4Q0CA026Q3
HIGH TEMP OP LIFE	1015	MAX705ESA+	135C	1000 HRS	79	0	NTOAH20A9FB
HIGH TEMP OP LIFE	1019	MAX3209EEUU+	135C	500 HRS	80	0	N8KAE2024C
HIGH TEMP OP LIFE	1021	MAX197BCWI+	135C	500 HRS	45	0	NGPBD3601Q1
HIGH TEMP OP LIFE	1021	MAX197BCWI+	135C	500 HRS	45	0	NGPBD3601Q2
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0935	MAX197BCWI+	150C	1000 HRS	78	0	NGPBD3586Q1
STORAGE LIFE	0935	MAX197BCWI+	150C	1000 HRS	78	0	NGPBD3586Q2
STORAGE LIFE	0935	MAX197BCWI+	150C	1000 HRS	76	0	NGPBD3586Q3
STORAGE LIFE	1010	MAX3241EEUI+	150C	1000 HRS	45	0	N4Q0CA026Q1
STORAGE LIFE	1010	MAX3241EEUI+	150C	1000 HRS	77	0	N4Q0CA026Q2
STORAGE LIFE	1010	MAX3241EEUI+	150C	500 HRS	77	0	N4Q0CA026Q3
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0935	MAX197BCWI+	-65C TO 150C	1000 CYS	78	0	NGPBD3586Q1
TEMP CYCLE, 5' RAMP, 10' DWELL	0935	MAX197BCWI+	-65C TO 150C	500 CYS	78	0	NGPBD3586Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	0935	MAX197BCWI+	-65C TO 150C	1000 CYS	76	0	NGPBD3586Q3
TEMP CYCLE, 5' RAMP, 10' DWELL	1010	MAX3241EEUI+	-65C TO 150C	1000 CYS	45	0	N4Q0CA026Q1
TEMP CYCLE, 5' RAMP, 10' DWELL	1010	MAX3241EEUI+	-65C TO 150C	1000 CYS	77	0	N4Q0CA026Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	1010	MAX3241EEUI+	-65C TO 150C	1000 CYS	77	0	N4Q0CA026Q3
TEMP CYCLE, 5' RAMP, 10' DWELL	1019	MAX3209EEUU+	-65C TO 150C	500 CYS	80	0	N8KAE2024C

Total: 0

FAILURE RATE: **MTTF (YRS): 99991** **QUANTITY: 602** **FAILS: 0** **FITS: 1.1**